TOSHIBA Transistor Silicon NPN Epitaxial Type

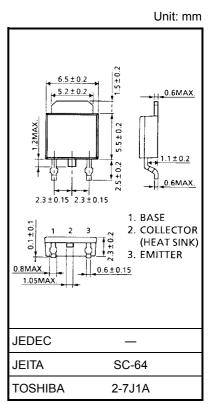
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High-Speed Swtching Applications DC-DC Converter Applications

- High DC current gain: $h_{FE} = 400$ to 1000 ($I_{C} = 0.5$ A)
- Low collector-emitter saturation: $V_{CE (sat)} = 0.22 \text{ V (max)}$
- High-speed switching: $t_f = 55$ ns (typ.)

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V_{CBO}	100	V	
Collector-emitter voltage		V_{CEX}	80	V	
		V_{CEO}	50		
Emitter-base voltage		V _{EBO}	7	V	
Collector current	DC	Ic	5	Α	
	Pulse	I _{CP}	10		
Base current		IB	0.5	Α	
Collector power dissipation	Ta = 25°C	Pc	1	W	
	Tc = 25°C	FC	20		
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	



Weight: 0.36 g (typ.)

Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I _{CBO}	$V_{CB} = 100 \text{ V}, I_E = 0$	_	_	100	nA
Emitter cut-off current		I _{EBO}	V _{EB} = 7 V, I _C = 0	_	_	100	nA
Collector-emitter brakedown voltage		V (BR) CEO	$I_C = 10 \text{ mA}, I_B = 0$	50	_	_	V
DC current gain		h _{FE} (1)	V _{CE} = 2 V, I _C = 0.5 A	400	_	1000	
		h _{FE} (2)	V _{CE} = 2 V, I _C = 1.6 A	200	_	_	
Collector-emitter saturation voltage		V _{CE (sat)}	I _C = 1.6 A, I _B = 32 mA	_	_	0.22	V
Base-emitter saturation voltage		V _{BE (sat)}	I _C = 1.6 A, I _B = 32 mA	_	_	1.10	V
Switching time	Rise time	t _r	See Figure 1 circuit diagram $V_{CC} \simeq 24 \text{ V, R}_L = 15 \Omega$ $I_{B1} = 32 \text{ mA, } I_{B2} = -53 \text{ mA}$	_	63	_	
	Storage time	t _{stg}		_	560	_	ns
	Fall time	t _f		_	55	_	

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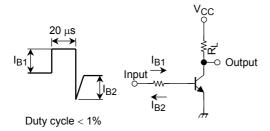
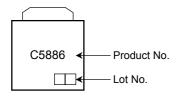
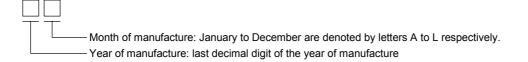


Figure 1 Switching Time Test Circuit & Timing Chart

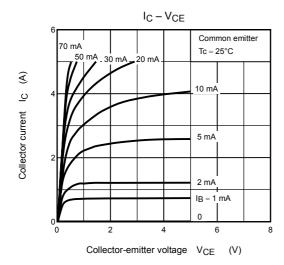
Marking

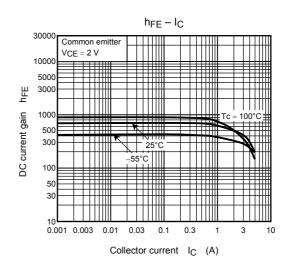


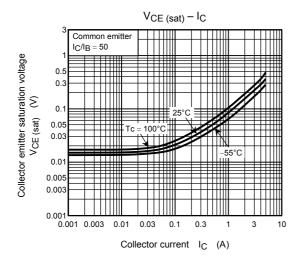
Explanation of Lot No.

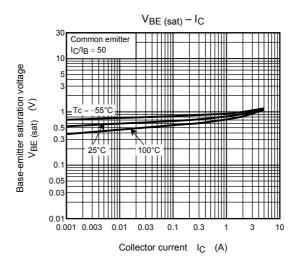


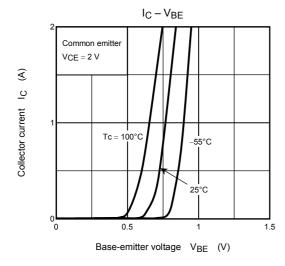
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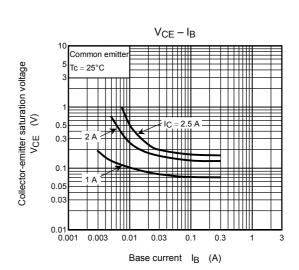


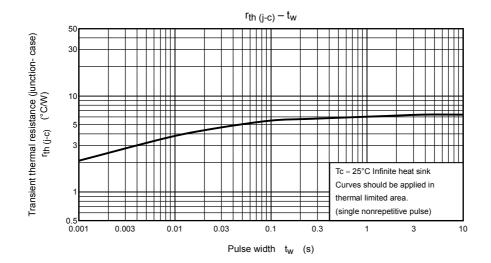


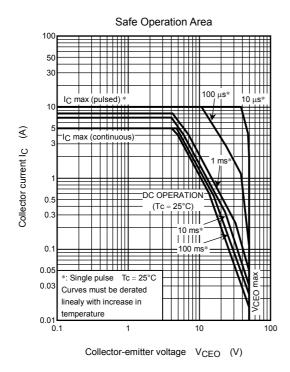












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